

## ISD 2023 - Week 2 Assignment

There are 10 questions for a total of 20 marks.

1. (2 marks) Consider a rectangular lattice where the atoms are spaced periodically with a lattice constant  $a$ . It is convenient to represent this lattice in the reciprocal (Fourier) space. The various segments in a reciprocal lattice are referred to as the Brillouin zones. Which of the following statements is/are true in a reciprocal lattice?

- A. the periodicity is  $2\pi/a$  in  $k$ -space**  
B. the periodicity in  $k$ -space is  $a$   
**C. the first Brillouin zone is from  $-\pi/a$  to  $+\pi/a$**   
D. the periodicity in  $k$ -space is  $2a$

2. (2 marks) Consider an intrinsic Silicon (bandgap 1.12 eV) at room temperature (300 K). Let the probability that a state located at the bottom of the conduction band is filled be ( $f_c$ ), and the probability that a state located at the top of the valence band is empty be ( $f_v$ ). Which of the following is true?

- A.  $f_c > f_v$    **B.  $f_c = f_v$**    C.  $f_c < f_v$    D.  $f_c + f_v = 0.5$

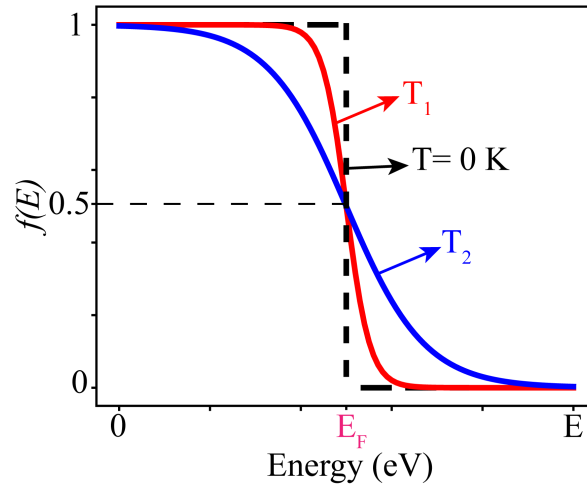
3. (2 marks) Consider intrinsic silicon at  $T=300$  K. What is the Fermi level position relative to the bottom of the conduction band? Assume  $N_c = 3 \times 10^{19} \text{ cm}^{-3}$ ,  $n_i = 1 \times 10^{10} \text{ cm}^{-3}$ .

- A. 0.56 eV below the conduction band**  
B. 0.56 eV above the conduction band  
C. 0.15 eV above the conduction band  
D. 0.15 eV below the conduction band

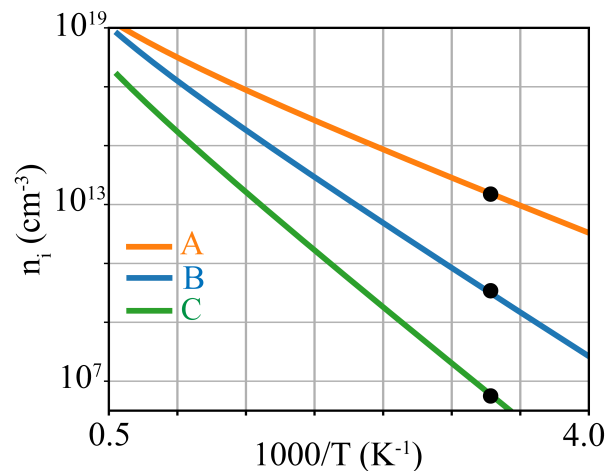
4. (2 marks) Consider n-type silicon at  $T=300$  K. What is the Fermi level position relative to the conduction band edge? Assume  $N_c = 3 \times 10^{19} \text{ cm}^{-3}$ ,  $n_i = 1 \times 10^{10} \text{ cm}^{-3}$  and  $N_D = 1 \times 10^{17} \text{ cm}^{-3}$ .

- A. 0.56 eV below the conduction band  
B. 0.56 eV above the conduction band  
C. 0.15 eV above the conduction band  
**D. 0.15 eV below the conduction band**

5. (2 marks) Consider the Fermi-Dirac distribution function ( $f(E)$ ) at different temperatures as shown in the figure. Which of the following statements is true regarding  $T_1, T_2$ ?



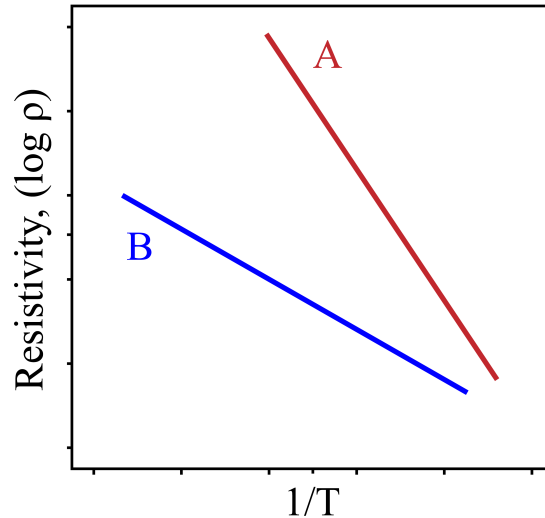
- A.  $T_2 = T_1 \neq 0$     **B.  $T_2 > T_1$**     C.  $T_2 < T_1$     D.  $T_2 = T_1 = 0$
6. (2 marks) Consider three typical semiconductors  $A$ ,  $B$  and  $C$  with bandgap  $E_{gA}$ ,  $E_{gB}$  and  $E_{gC}$  respectively. The intrinsic carrier concentration  $n_i$  of three materials as a function of temperature  $1/T$  is shown in the figure. Which of the following is true regarding their bandgap?



- A.  $E_{gA} < E_{gB} < E_{gC}$**     B.  $E_{gB} < E_{gA} < E_{gC}$     C.  $E_{gA} > E_{gB} > E_{gC}$     D.  $E_{gB} > E_{gA} > E_{gC}$

**Reflect and remember:** The intrinsic carrier concentration increased by over 4 orders of magnitude as the temperature increased by 150 K. Why does the intrinsic carrier density increase with increasing temperature? Also, notice that at high temperatures  $n_i$  seems to converge to a particular number. What is this limit of  $n_i$  at very high temperatures?

7. (2 marks) Consider two non-degenerate semiconductors  $A$  and  $B$  with bandgap  $E_{gA}$  and  $E_{gB}$  respectively. The resistivities  $\rho$  of these two materials ( $\rho_A$  and  $\rho_B$ ) reduce with the reciprocal of temperature  $1/T$  as shown in the figure. Which of the following is true regarding their bandgap?



- A.  $E_{gA} = E_{gB} \neq 0$     **B.  $E_{gA} > E_{gB}$**     C.  $E_{gA} < E_{gB}$     D.  $E_{gA} = E_{gB} = 0$
8. (2 marks) **(GATE-EC2022)** In a non-degenerate bulk semiconductor with electron density  $n = 10^{16} \text{ cm}^{-3}$ , the value of  $E_C - E_{Fn} = 200 \text{ meV}$ , where  $E_C$  and  $E_{Fn}$  denote the bottom of the conduction band energy and electron Fermi level energy, respectively. Assume the thermal voltage as 26 mV and the intrinsic carrier concentration is  $10^{10} \text{ cm}^{-3}$ . For  $n = 0.5 \times 10^{16} \text{ cm}^{-3}$ , the closest approximation of the value of  $(E_C - E_{Fn})$ , among the given options is \_\_\_\_\_ meV.
- A. 165  
B. 235  
**C. 218**  
D. 182
9. (2 marks) **(GATE-EC2023)** In a semiconductor, the Fermi energy level lies 0.35 eV above the valence band. The effective density of states in the valence band at  $T=300 \text{ K}$  is  $1 \times 10^{19} \text{ cm}^{-3}$ . The thermal equilibrium hole concentration in silicon at 400 K is \_\_\_\_\_  $\times 10^{13} \text{ cm}^{-3}$ . Given  $kT = 0.026 \text{ eV}$ . (Recall, effective density of states  $N_v$  depends on effective mass and temperature)
- A. 36    B. 92    **C. 63**    D. 25

10. (2 marks) Consider a silicon sample doped with  $10^{17} \text{ cm}^{-3}$  phosphorus atoms. Assume the donor energy level is  $45 \text{ meV}$  below  $E_c$  for phosphorus. We have seen that at  $T = 0 \text{ K}$  the dopant atoms are not ionized (*i.e., the excess electron is at the dopant site and cannot move around the lattice.*). At higher temperatures, some of the dopants are ionized and they contribute to electrons in the conduction band. Estimate the probability of 'finding' an electron at the donor energy level at  $T = 300 \text{ K}$  by calculating  $E_D - E_F$ . Based on this can you infer what fraction of the donors are "not ionized"? You may assume that an electron at  $E_D$  implies that the corresponding fraction of dopant atoms are not ionized.

- A. 100 %
- B. 2.3 %**
- C. 65 %
- D. 20 %

**Reflect and remember:** You will notice that as  $N_d$  increases,  $E_F$  moves toward  $E_D$ , and the probability of non-ionization can become quite large. In reality, the impurity level broadens into an impurity band that merges with the conduction band in heavily doped semiconductors (*i.e., when donors or acceptors are close to one another*). This happens for the same reason energy levels broaden into bands when atoms are brought close to one another to form a crystal. The electrons in the impurity band are also in the conduction band.

**Therefore, the assumption of  $n = N_d$  (or complete ionization) is reasonable even at very high doping densities. The same holds true in P-type materials.**

Refer Donald Neamen, Semiconductor Physics and Devices, 4th Edition, page no. 118-120 for additional details.